

FORM PTO-1449

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)



Attorney Docket Number	40954/DBP/E43
Application Number	09/700,572
Filing Date	November 15, 2000
Applicant(s)	Karl Heinz Munzke, et al.
Group Art Unit	2877
Examiner Name	Not Yet Assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
120	WO 97/18461	05/1997	WIPO (English translation of claims only)				

OTHER DOCUMENTS

EXAMINER INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
120	English translation of previously filed German Article, Technologieland Nordrhein-Westfalen, "Tagungsunterlagen," Entire Document, 5. und 6. September 1996, Aachen, Karman-Auditorium; entitled "Current Developments and Industrial Use of Image Processing; Measuring Image Processing in Automation Technology"
	English translation of previously German Article "Industrielle Bildverarbeitung/Machine Vision, Markte Trends Bezugsquellen, Fachgemeinschaft Robotik + Automation (no date) 2 pages; entitled "Industrial Image Processing/Machine Vision"
120	English translation of previously filed German Article, Technologieland Nordrhein-Westfalen, "Tagungsband" Entire Document, 11. und 12. September 1997, Aachen, Karman-Auditorium; entitled: "Current Developments and Implementation of Image Processing; Overview of industrial applications of clear text and bar code identification"
120	English translation of previously filed German Article, "Einsatz der Bildverarbeitung zur Druckvollständigkeitskontrolle," Entire Document, 11. und 12. September 1997, Aachen; entitled "Use of image processing for checking printing completeness"

EXAMINER SIGNATURE	<i>Dr. A. J. [Signature]</i>	DATE CONSIDERED	<i>11/15/00</i>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Patent and Trademark Office, U.S. DEPARTMENT OF COMMERCE

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	Group Art Unit	Not yet assigned
	Examiner Name	Not yet assigned

U.S. PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DB	5,486,692	01/1996	Baldwin	250	223 B	

FOREIGN PATENT DOCUMENTS							
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						YES	NO
DB	WO 97/18461	05/1997	WIPO				
DB	WO 98/04882	05/1998	WIPO				

OTHER DOCUMENTS	
EXAMINER INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
DB	O'GORMAN, "Subpixel Precision of Straight-Edged Shapes for Registration and Measurement", IEEE Transactions on Pattern Analysis and Machine Intelligence, July 1996, pgs. 746-751, Vol. 18, No 7
DB	STANKE ET AL., "High-Precision and Versatile Optical Measurement of Different Sides of IC's in the Confectioning Process using only one Viewpoint", Proceedings of the 24th Annual Conference of the IEEE Industrial Electronics Society, AACHEN, Germany, August 31, 1998 - September 4, 1998, pgs. 2425-2427

EXAMINER SIGNATURE		DATE CONSIDERED	6/30/03
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						YES	NO

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<i>JS</i>	German Article, Technologieland Nordrhein-Westfalen, "Tagungsunterlagen," Entire Document, 5. und 6. September 1996, Aachen, Karman-Auditorium
	German Article "Industrielle Bildverarbeitung/Machine Vision, Markte Trends Bezugsquellen, Fachgemeinschaft Robotik + Automation (no date) 2 pages
<i>JS</i>	German Article, Technologieland Nordrhein-Westfalen, "Tagungsband" Entire Document, 11. und 12. September 1997, Aachen, Karman-Auditorium
<i>RK</i>	German Article, "Einsatz der Bildverarbeitung zur Druckvollständigkeitskontrolle," Entire Document, 11. und 12. September 1997, Aachen.
	ICOS; "3D Lead inspection Module (LHM)," Entire Document.
<i>MS</i>	www.trigonadcotech.com, "SMD 9000 Automated Inspection System for Surface Mount Devices," Entire Document, SMD 9000 product data sheet 2/25/97.

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